

**Search Notes**

Application/Control No.

10/730,151

Examiner

James D. Stein

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

2874

**SEARCHED**

Class	Subclass	Date	Examiner
385	27,42, 45, 47	9/8/2005	JDS
398	33	9/8/2005	JDS

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
385	27,42,45	9/8/2005	JDS
385	47	9/8/2005	JDS
398	33	9/8/2005	JDS

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See attached EAST search history	9/8/2005	JDS
IEEE INSPEC: waveguide, couple, common region, zone, area, TE and TM polarization	9/8/2005	JDS
USPGPUB interference search -- see attached EAST search history	9/8/2005	JDS
385/14-52 -- keyword search	9/8/2005	JDS